

Notice of References Cited

Application/Control No.

10/536,986

Applicant(s)/Patent Under
Reexamination
NISHIO ET AL.

Examiner

Liam J. Heincer

Art Unit

1709

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,874,825 A	10-1989	Gergen, William P.	525/425
*	B	US-5,609,795 A	03-1997	Matsumoto et al.	252/500
*	C	US-5,654,393 A	08-1997	Kemmish et al.	528/125
*	D	US-5,658,687 A	08-1997	Takeda et al.	429/317
*	E	US-5,840,809 A	11-1998	Ohtsuka et al.	525/316
*	F	US-5,830,974 A	11-1998	Schmidhauser et al.	528/125
*	G	US-5,968,681 A	10-1999	Miura et al.	429/122
*	H	US-6,077,627 A	06-2000	Bauerlein, Peter	429/309
*	I	US-6,180,287 B1	01-2001	Watanabe et al.	429/312
*	J	US-6,235,866 B1	05-2001	Khoury et al.	528/125
*	K	US-2001/0006677 A1	07-2001	MCGINITY et al.	424/449
*	L	US-6,287,411 B1	09-2001	Kelley et al.	156/327
*	M	US-2002/0034689 A1	03-2002	Hoshida et al.	429/254

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200184659 A1	11-2001	World Intellect	DESCHAMPS et al.	
	O	WO 2003002669 A1	01-2003	World Intellect	FUJII et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0045685 A1	04-2002	Ogoe et al.	524/35
*	B	US-2002/0103327 A1	08-2002	CLAUB et al.	528/125
*	C	US-2002/0128364 A1	09-2002	Michot et al.	524/401
*	D	US-2003/0044688 A1	03-2003	Kang et al.	429/317
*	E	US-2003/0091898 A1	05-2003	Dexter et al.	429/209
*	F	US-2003/0094599 A1	05-2003	Le et al.	252/500
*	G	US-6,576,692 B1	06-2003	Ohtsuka et al.	524/151
*	H	US-2003/0108799 A1	06-2003	Lascaud et al.	429/316
*	I	US-2003/0170546 A1	09-2003	Boon et al.	429/317
*	J	US-2003/0165743 A1	09-2003	HORIKIRI et al.	429/300
*	K	US-6,620,879 B1	06-2003	Albrecht et al.	524/522
*	L	US-2004/0007688 A1	01-2004	Awano et al.	252/62.2
*	M	US-2004/0023114 A1	02-2004	Sada et al.	429/231.4

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,773,810 B2	08-2004	Sen et al.	428/370
*	B	US-6,849,706 B1	02-2005	Brunelle et al.	528/170
*	C	US-2005/0048236 A1	03-2005	Watkins et al.	428/035.7
*	D	US-6,949,285 B1	09-2005	Tobinaga et al.	428/317.9
*	E	US-6,939,383 B2	09-2005	Eastin et al.	29/623.1
*	F	US-2006/0040196 A1	02-2006	Yano et al.	430/109.1
*	G	US-7,125,953 B2	10-2006	Lockley et al.	528/480
*	H	US-7,241,835 B2	07-2007	O'Brien et al.	524/862
	T	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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